



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re patent application of

Hamid K. Aghajan

Serial No.: 09/365,517

Filed: August 2, 1999

For: Two-Dimensional Scatter Plot  
Technique for Defect Detection

Group Art Unit: 2625

Examiner: S. C. Chawan

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Technology Center 2600

CERTIFICATE OF MAILING under 37 C.F.R. 1.8(a)

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*Michael B. Einschlag*  
Michael B. Einschlag

January 3, 2003  
Date of Signature

Commissioner for Patents  
Washington, D.C. 20231

Sir:

This is in response to the outstanding Office Action mailed November 6, 2002.